# Cascade Microtech and Agilent Technologies Parametric Probing Seminar

Identify and discuss problems and challenges in making RF and DC/CV measurements. Learn how these can be overcome to ensure absolute confidence in your results.
Seminar Agenda:
8 - 8:30 a.m.
Continental Breakfast & Registration
8:30 - 9:30 a.m.
Making Matching Measurements for Use in IC Design Bill Verzi, Agilent Technologies
&#149 Matching terminology and applications
&#149 Matching requirements for different device types
&#149 Methods to minimize or eliminate measurement error
&#149 Techniques to extend measurement accuracy beyond published specs
&#149 Tips for effective matching characterization
9:30 - 10:30 a.m.
Parallel Parametric Reliability
Louis Solis, Agilent Technologies
&#149 Limitations of current reliability testing solutions
&#149 Reliability algorithms required by modern processes
&#149 Parallel Parametric Reliability: Features and Benefits
&#149 Case studies and measurement results
10:45 - 11:45 a.m.
Increasing On-wafer IV Measurement Speed & Accuracy Using Agilent 4156C & E5270 Series Parametric Measurement Solutions
Terry Burcham, Cascade Microtech
&#149 Fundamentals of guarding and shielding techniques
&#149 Impact of residual capacitance on speed and accuracy
&#149 Methods to evaluate the IV measurement system
Noon - 1 p.m.
Lunch and Product Fair
1 - 2 p.m.
Optimizing On-wafer CV Measurements Using Agilent 4284A and 4294A
Terry Burcham, Cascade Microtech
&#149 Fundamentals of capacitance measurements
&#149 Optimizing the test configurations
&#149 Correlation of measurements 2:15 - 3:15 p.m.
Improving On-wafer S-parameter Calibration & Accuracy Using Agilent PNA Series Vector Network Analyzers
Terry Burcham, Cascade Microtech
&#149 Fundamentals of calibration methods
&#149 Verification of calibrations
&#149 Troubleshooting techniques Limited to the first 40 registrants!
Contact Junko Nakaya at Cascade Microtech.

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